



FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE							ATTORNEY DOCKET NO. 1945 P2/SILICON/MBE				SERIAL NO 09/362,924			
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)											APPLICANT CHOW, ET AL.					
											FILING DATE JULY 27, 1999					GROUP 1746
<b>U.S. PATENT DOCUMENTS</b>																
Examiner Initial		DOCKET NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE			
<i>AWC</i>	AA	5	1	5	8	6	4	4	10/27/92	CHEUNG, ET AL.	156	643				
<i>AWC</i>	AB	5	2	8	1	3	0	2	01/25/94	GABRIC, ET AL.	156	643				
<i>AWC</i>	AC	5	3	7	8	3	1	1	01/03/95	NAGAYAMA, ET AL.	156	643				
<i>AWC</i>	AD	5	7	6	7	0	2	1	06/16/98	IMAI, ET AL.	438	719				
<i>AWC</i>	AE	5	7	8	8	7	9	9	08/04/98	STEGER, ET AL.	156	345				
<i>AWC</i>	AF	5	8	4	3	2	3	9	12/01/98	SHROTRIYA	134	1.1				
<i>AWC</i>	AG	5	8	6	9	4	0	1	02/09/99	BRUNEMEIER, ET AL.	438	710				
	AH															
	AI															
	AJ															
	AK															
<b>FOREIGN PATENT DOCUMENTS</b>																
		DOCKET NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION			
													YES	NO		
<i>AWC</i>	AL	0	2	7	2	1	4	3	06/22/88	EP APPLICATION						
<i>AWC</i>	AM	0	3	1	4	9	9	0	05/10/89	EP APPLICATION						
<i>AWC</i>	AN	0	7	4	6	0	1	5	12/04/96	EP APPLICATION						
<i>AWC</i>	AO	6	1	7	7	0	9	2	06/24/94	JAPAN			✓			
<i>AWC</i>	AP	7	0	2	9	8	7	9	01/31/95	JAPAN			✓			
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)</b>																
<i>AWC</i>	AQ	PCT Search Report dated October 28, 1999														
	AR															
	AS															
EXAMINER <i>AWC</i>										DATE CONSIDERED <i>5/24/01</i>						
EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.																